FROM AP PRODUCTS TEST CLIPS for SMALL OUTLINE INTEGRATED CIRCUITS (SOIC's)

Whatever direction the state-of-the-art takes in PC board components, AP PRODUCTS is right there with test clips that provide the performance and reliability that you've come to expect.

That's exactly the case with our newest line of test clips, a downsized series made for today's smaller components and higher densities. Now normally hard-to-access SOICs can be connected to test probes quickly and easily without the risk of shorting out chips or damaging other board components.

A P PRODUCTS' SOIC test clips are available in different pin sizes to accommodate a wide range of requirements.

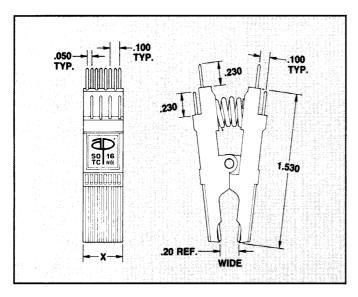
Industry standard .025" square contact pins on .050" centers are staggered to permit easy attachment of female socket connectors or wire wrapping and help prevent shorting of adjacent probes. With these smaller test clips, you can stack SOICs as close as .025" end to end.

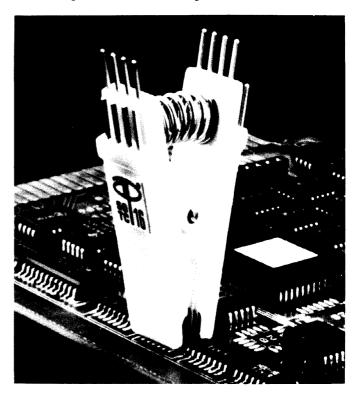
Like our other test clips, the SOIC series features heavy duty helical compression springs that provide firm, positive contact pressure, an insulating contact comb to prevent accidental shorts and a patented wiping action to ensure integrity in testing.

The steel hinge pin and tough acetal body provide long service life. Available in gold or alloy 770, use these SOIC test clips for all your test and prototype needs.

WIDE - Part Numbers

No. Pins	X Dim.	Alloy	Gold
16	.420	923660-16	923665-16
18	.470	923660-18	923665-18
20	.520	923660-20	923665-20
24	.620	923660-24	923665-24
28	.720	923660-28	923665-28





NARROW – Part Numbers

No. Pins	X Dim.	Alloy	Gold
8	.420	923650-08	923655-08
14	.370	923650-14	923655-14
16	.420	923650-16	923655-16

